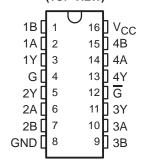
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- Meet or Exceed the Requirements of TIA/EIA-422-B, TIA/EIA-423-B, and TIA/EIA-485-A and ITU Recommendations V.10, V.11, X.26, and X.27
- **Designed for Multipoint Bus Transmission** on Long Bus Lines in Noisy Environments
- **3-State Outputs**
- Common-Mode Input Voltage Range of -12 V to 12 V
- Input Sensitivity ±200 mV
- Input Hysteresis 50 mV Typ
- High Input Impedance 12 k Ω Min
- **Operate From Single 5-V Supply**
- **Low Power Requirements**
- Plug-In Replacement for AM26LS32

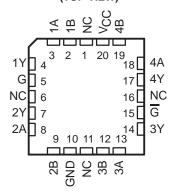
description

The SN55173, SN65173, and SN75173 are monolithic quadruple differential line receivers with 3-state outputs. They are designed to meet requirements of TIA/EIA-422-B, TIA/EIA-423-B, TIA/EIA-485-A, and several ITU recommendations. The standards are for balanced multipoint bus transmission at rates up to 10 megabits per second. The four receivers share two OR enable inputs, one active when high, the other active when low. These devices feature high input impedance, input hysteresis for increased noise immunity, and input sensitivity of ±200 mV over a common-mode input voltage range of -12 to 12 V. Fail-safe design specifies that if the inputs are open circuited, the outputs are always high. The SN65173 and SN75173 are designed for optimum performance when used with the SN75172 or SN75174 quad differential line drivers.

SN55173...J PACKAGE **SN65173, SN75173...D OR N PACKAGE** (TOP VIEW)



SN55173...FK PACKAGE (TOP VIEW)



NC-No internal connection

THE SN55173 IS NOT RECOMMENDED FOR NEW DESIGNS.

The SN55173 is characterized over the full military temperature range of -55°C to 125°C. The SN65173 is characterized for operation from -40°C to 85°C. The SN75173 is characterized for operation from 0°C to 70°C.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

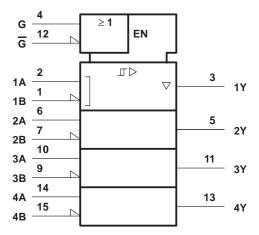


FUNCTION TABLE (each receiver)

DIFFERENTIAL	ENA	BLES	OUTPUT	
A–B	G	G	Υ	
V>02V	Н	Χ	Н	
V _{ID} ≥ 0.2 V	Χ	L	Н	
0.2 \/ 4 \/ \= 4 0.2 \/	Н	Х	?	
-0.2 V < V _{ID} < 0.2 V	Χ	L	?	
V-> < 0.2 V	Н	Х	L	
V _{ID} ≤ -0.2 V	Χ	L	L	
X	L	Н	Z	
Open circuit	Х	L	Н	
Open circuit	Н	Χ	Н	

H = high level, L = low level, ? = indeterminate, X = irrelevant, Z = high impedance (off)

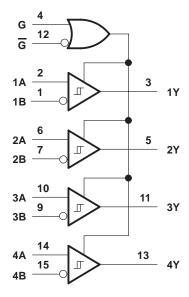
logic symbol †



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12. Pin numbers shown are for the D, J, and N packages.

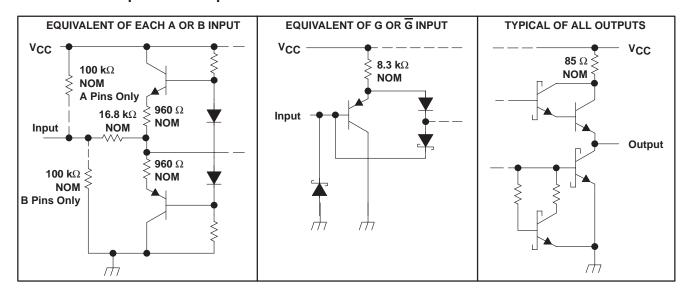


logic diagram (positive logic)



Pin numbers shown are for the D, J, and N packages.

schematics of inputs and outputs



SN55173, SN65173, SN75173 QUADRUPLE DIFFERENTIAL LINE RECEIVERS

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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage, V _{CC} (see Note 1)	
Input voltage (V _I or B inputs)	
Differential input voltage, V _{ID} (see Note 2)	±25 V
Enable input voltage, V _I	7 V
Low-level output current, I _{OL}	50 mA
Continuous total dissipation	See Dissipation Rating Table
Storage temperature range, T _{stq}	65°C to 150°C
Case temperature for 60 seconds, T _C : FK package	260°C
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds: D or N packa	ge 260°C
Lead temperature 1,6 mm (1/16 inch) from case for 60 seconds: J package .	300°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. All voltage values, except differential input voltage, are with respect to network ground terminal.

2. Differential-input voltage is measured at the noninverting input with respect to the corresponding inverting input.

DISSIPATION RATING TABLE

PACKAGE	$T_{\mbox{\scriptsize A}} \le 25^{\circ}\mbox{\scriptsize C}$ POWER RATING	DERATING FACTOR	T _A = 70°C POWER RATING	T _A = 125°C POWER RATING
D	950 mW	7.6 mW/°C	608 mW	_
FK	1375 mW	11.0 mW/°C	880 mW	275 mW
J	1375 mW	11.0 mW/°C	880 mW	275 mW
N	1150 mW	9.2 mW/°C	736 mW	_

recommended operating conditions

			MIN	NOM	MAX	UNIT
Owner have a Kenner V	SN55173		4.5	5	5.5	V
Supply voltage, V _{CC}	SN65173, SN75173		4.75	5	5.25	V
Common-mode input voltage, V _{IC}					±12	V
Differential input voltage, V _{ID}				±12	V	
High-level enable-input voltage, VIH		2			V	
Low-level enable-input voltage, V _{IL}					0.8	V
High-level output current, IOH					-400	μΑ
Low-level output current, I _{OL}				16	mA	
	SN55173		-55		125	
Operating free-air temperature, TA	SN65173		-40		85	°C
	SN75173		0		70	

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electrical characteristics over recommended ranges of common-mode input voltage, supply voltage, and operating free-air temperature

	PARAMETER	TES	T CONDITIONS		MIN	TYP [†]	MAX	UNIT
V _{IT+}	Positive-going input threshold voltage	$V_0 = 2.7 V$,	$I_{O} = -0.4 \text{ mA}$				0.2	V
V _{IT} _	Negative-going input threshold voltage	$V_0 = 0.5 V$,	I _O = 16 mA		-0.2‡			V
V _{hys}	Hysteresis (V _{IT+} – V _{IT} –)	See Figure 4				50		mV
VIK	Enable-input clamp voltage	$I_{I} = -18 \text{ mA}$					-1.5	V
			I _{OH} = -400 μA	SN55173	2.5			V
VOH	High-level output voltage	$V_{ID} = 200 \text{ mV},$		SN65173, SN75173	2.7			V
V	Low level output voltage	$V_{ID} = -200 \text{ mV}$. See Figure 1	Can Figure 4	$I_{OL} = 8 \text{ mA}$			0.45	V
VOL	Low-level output voltage		I _{OL} = 16 mA			0.5	V	
loz	High-impedance-state output current	$V_0 = 0.4 \text{ V to } 2.4 \text{ V}$					±20	μΑ
1.	Line input current	Other input et 0 V	Soo Noto 2	V _I = 12 V	T		1	mA
اا	Line input current	Other input at 0 v,	other input at 0 V. See Note 3	V _I = -7 V			-0.8	IIIA
lн	High-level enable-input current	V _{IH} = 2.7 V					20	μΑ
I _{IL}	Low-level enable-input current	V _{IL} = 0.4 V					-100	μΑ
rį	Input resistance		·		12		·	kΩ
los	Short-circuit output current				-15		-85	mA
Icc	Supply current	Outputs disabled					70	mA

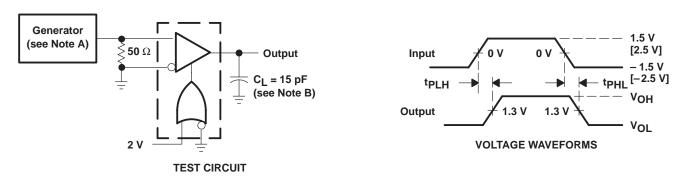
NOTE 3: Refer to TIA/EIA-422-B and TIA/EIA-423-B for exact conditions.

switching characteristics, $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
tPLH	Propagation delay time, low-to-high-level output	$V_{ID} = -1.5 \text{ V to } 1.5 \text{ V,}$ $C_{L} = 15 \text{ pF,}$ See Figure 1			20	35	ns
tPHL	Propagation delay time, high-to-low-level output				22	35	ns
tPZH	Output enable time to high level	$C_L = 15 pF$,	See Figure 2		17	22	ns
tpzL	Output enable time to low level	$C_L = 15 pF$,	See Figure 3		20	25	ns
tPHZ	Output disable time from high level	$C_L = 5 pF$,	See Figure 2		21	30	ns
t _{PLZ}	Output disable time from low level	$C_L = 5 pF$,	See Figure 3		30	40	ns

[†] All typical values are at V_{CC} = 5 V, T_A = 25°C. ‡ The algebraic convention, in which the less positive (more negative) limit is designated as minimum, is used in this data sheet for threshold voltage levels only.

PARAMETER MEASUREMENT INFORMATION

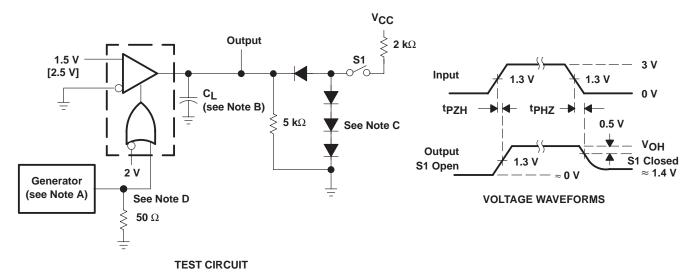


[] represent voltages on the SN55173 only.

NOTES: A. The input pulse is supplied by a generator having the following characteristics: PRR = 1 MHz, duty cycle = 50%, $t_r \le 6$ ns, $t_f \le 6$ ns, t_f

B. CL includes probe and jig capacitance.

Figure 1. tplH, tpHL Test Circuit and Voltage Waveforms



[] represent voltages on the SN55173 only.

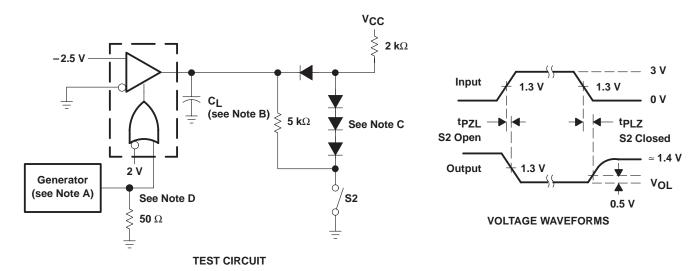
NOTES: A. The input pulse is supplied by a generator having the following characteristics: PRR = 1 MHz, duty cycle = 50%, $t_r \le 6$ ns, $t_f \le 6$ ns, t_f

- B. C_L includes probe and jig capacitance.
- C. All diodes are 1N916 or equivalent.
- D. To test the active-low enable \overline{G} , ground G and apply an inverted input waveform to \overline{G} .

Figure 2. t_{PHZ}, t_{PZH} Test Circuit and Voltage Waveforms



PARAMETER MEASUREMENT INFORMATION

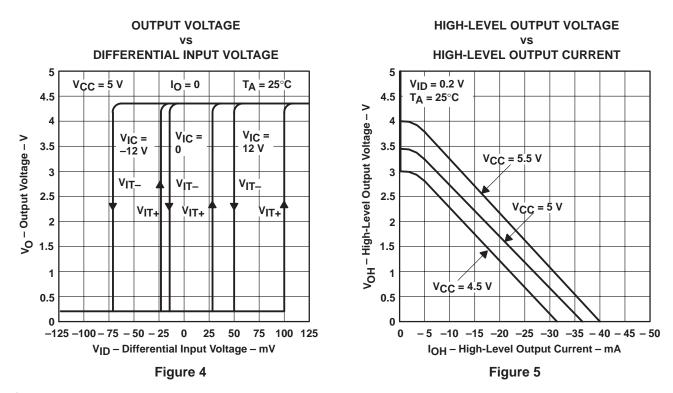


NOTES: A. The input pulse is supplied by a generator having the following characteristics: PRR = 1 MHz, duty cycle = 50%, $t_f \le 6$ ns, t_f

- B. C_L includes probe and jig capacitance.
- C. All diodes are 1N916 or equivalent.
- D. To test the active-low enable \overline{G} , ground G and apply an inverted input waveform to \overline{G} .

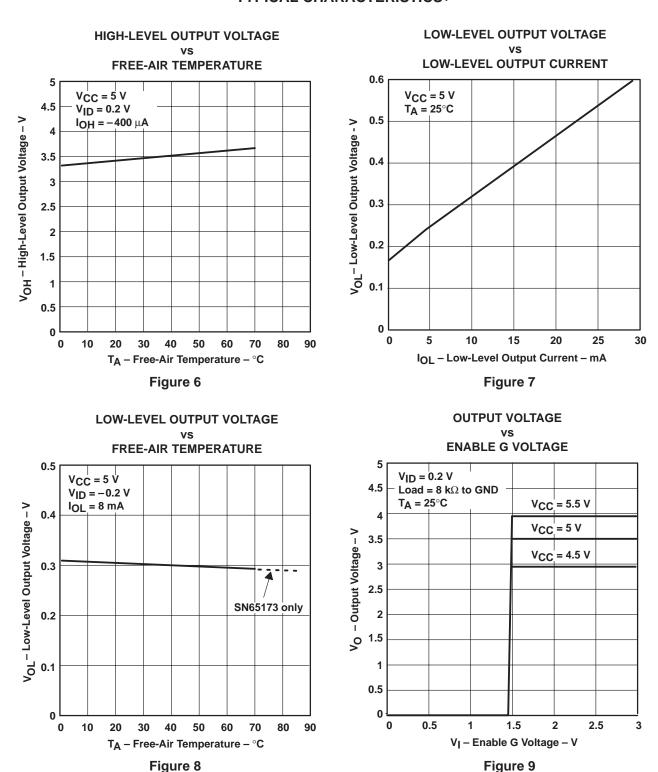
Figure 3. tpzl, tpLZ Test Circuit and Voltage Waveforms

TYPICAL CHARACTERISTICS[†]



[†] Operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied.

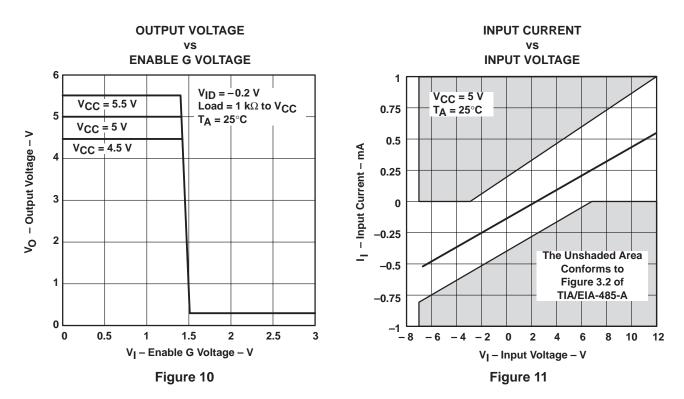
TYPICAL CHARACTERISTICS†



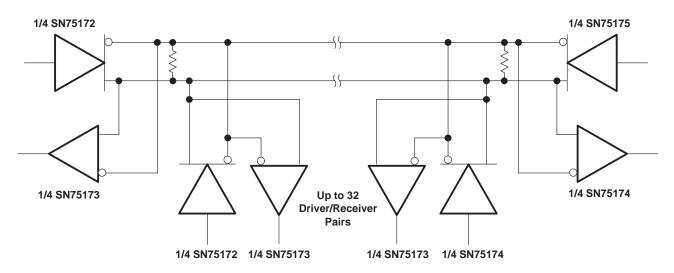
[†] Operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied.



TYPICAL CHARACTERISTICS



APPLICATION INFORMATION



NOTE A: The line should be terminated at both ends in its characteristic impedance. Stub lengths off the main line should be kept as short as possible.

Figure 12. Typical Application Circuit



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